



# FQB19N20C/FQI19N20C

### 200V N-Channel MOSFET

#### **General Description**

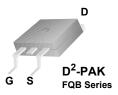
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switched mode power supplies, active power factor correction, electronic lamp ballasts based on half bridge topology.

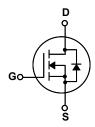
#### **Features**

- 19.0A, 200V,  $R_{DS(on)}$  = 0.17 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 40.5 nC)
- Low Crss (typical 85 pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- RoHS Compliant









## Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQB19N20C / FQI19N20C	Units
V <sub>DSS</sub>	Drain-Source Voltage		200	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)		19.0	Α
	- Continuous (T <sub>C</sub> = 100°C)		12.1	Α
$I_{DM}$	Drain Current - Pulsed	(Note 1)	76.0	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	433	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	19.0	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	13.9	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
	Power Dissipation ( $T_A = 25^{\circ}C$ )*  Power Dissipation ( $T_C = 25^{\circ}C$ )		3.13	W
$P_D$			139	W
	- Derate above 25°C		1.11	W/°C
$T_J$ , $T_{STG}$	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

### **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.9	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient*		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 250 μA				V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.24		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V			10	μΑ
		V <sub>DS</sub> = 160 V, T <sub>C</sub> = 125°C			100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 9.5 A		0.14	0.17	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 9.5 A (Note 4)		10.8		S
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input Capacitance Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		830 195 85	1080 255 110	pF pF pF
	·			85	110	pF
	ing Characteristics	I	1			
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 100 V, I <sub>D</sub> = 19.0 A,		15	40	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		150	310	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	(Note 4, 5)		135	280	ns
t <sub>f</sub>	Turn-Off Fall Time	, ,		115	240	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 160 V, I <sub>D</sub> = 19.0 A,		40.5	53.0	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V		6.0		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		22.5		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				19.0	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				76.0	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 19.0 A			1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 19.0 A,		208		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		1.63		μС

- $\label{eq:Notes:Notes:1} \begin{tabular}{ll} \textbf{Notes:} \\ \textbf{1.} & \textbf{Repetitive Rating: Pulse width limited by maximum junction temperature} \\ \textbf{2.} & \textbf{L} = \textbf{1.8mH, } \textbf{I}_{AS} = \textbf{19.0A, } \textbf{V}_{DD} = \textbf{50V, } \textbf{R}_{G} = \textbf{25} \ \Omega, \textbf{Starting} \quad \textbf{T}_{J} = \textbf{25}^{\circ} \textbf{C} \\ \textbf{3.} & \textbf{I}_{SD} \leq \textbf{19.0A, } \textbf{di/dt} \leq \textbf{300A/\mus, } \textbf{V}_{DD} \leq \textbf{BV}_{DSS, } \textbf{Starting} \quad \textbf{T}_{J} = \textbf{25}^{\circ} \textbf{C} \\ \textbf{4.} & \textbf{Pulse Test: Pulse width} \leq \textbf{300\mus, Duty cycle} \leq \textbf{2\%} \\ \textbf{5.} & \textbf{Essentially independent of operating temperature} \\ \end{tabular}$

# **Typical Characteristics**

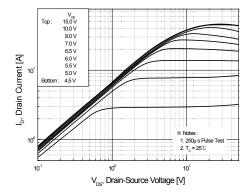


Figure 1. On-Region Characteristics

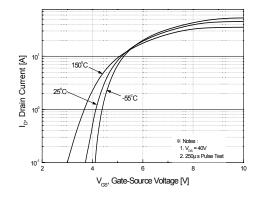


Figure 2. Transfer Characteristics

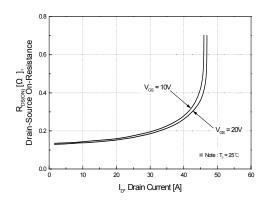


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

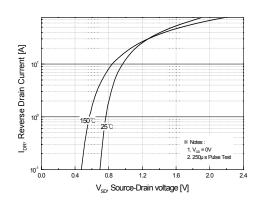


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

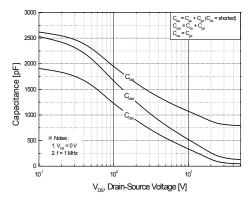


Figure 5. Capacitance Characteristics

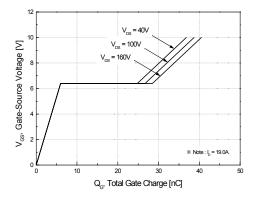
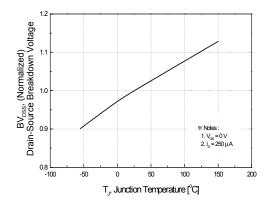


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)



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Figure 7. Breakdown Voltage Variation vs Temperature

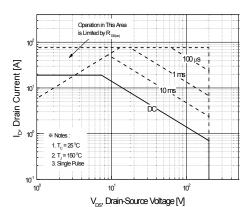


Figure 8. On-Resistance Variation vs Temperature

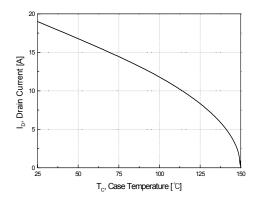


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

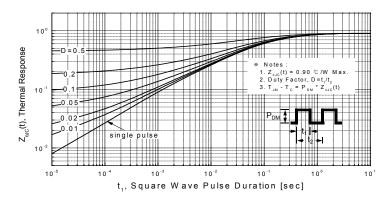
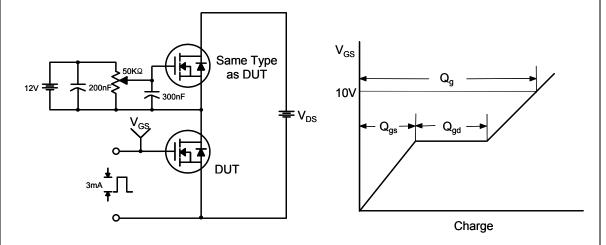


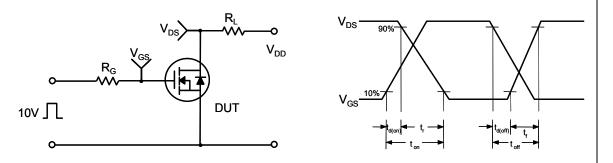
Figure 11. Transient Thermal Response Curve

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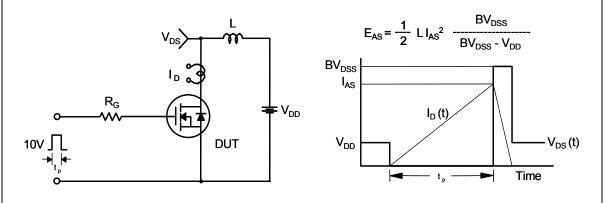
# **Gate Charge Test Circuit & Waveform**



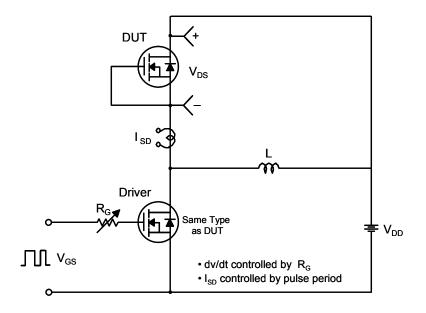
# **Resistive Switching Test Circuit & Waveforms**

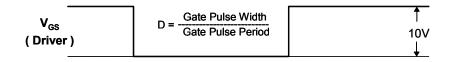


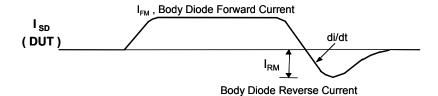
### **Unclamped Inductive Switching Test Circuit & Waveforms**

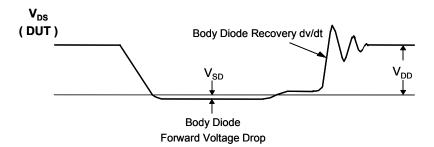


### Peak Diode Recovery dv/dt Test Circuit & Waveforms



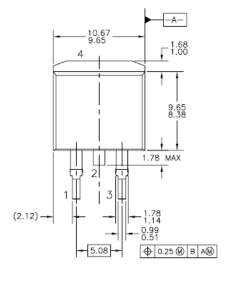


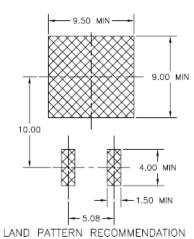


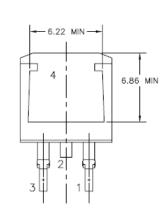


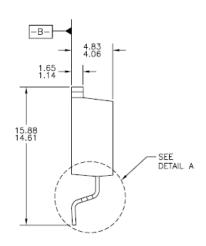
### **Mechanical Dimensions**

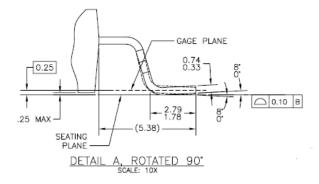
# D<sup>2</sup> - PAK









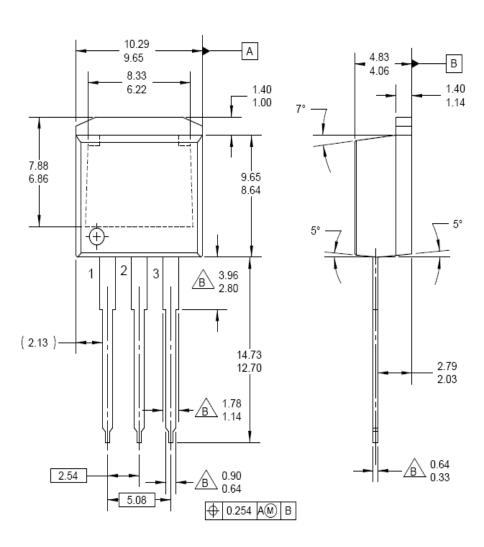


Dimensions in Millimeters

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# **Mechanical Dimensions**

I<sup>2</sup> - PAK



Dimensions in Millimeters





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